

Description

The VSM82P06 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge .This device is well suited for high current load applications.

General Features

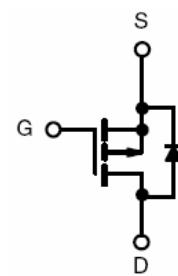
- $V_{DS} = -60V, I_D = -82A$
- $R_{DS(ON)} < 13m\Omega @ V_{GS} = -10V$
- $R_{DS(ON)} < 16m\Omega @ V_{GS} = -4.5V$
- High density cell design for ultra low $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

- Load switch



TO-252



Schematic Diagram

Package Marking and Ordering Information

| Device Marking | Device | Device Package | Reel Size | Tape width | Quantity |
|----------------|----------|----------------|-----------|------------|----------|
| VSM82P06-T2 | VSM82P06 | TO-252 | - | - | - |

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

| Parameter | Symbol | Limit | Unit |
|--|---------------------|------------|---------------|
| Drain-Source Voltage | V_{DS} | -60 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Drain Current-Continuous | I_D | -82 | A |
| Drain Current-Continuous($T_c=100^\circ C$) | $I_D (100^\circ C)$ | -58 | A |
| Pulsed Drain Current | I_{DM} | -328 | A |
| Maximum Power Dissipation | P_D | 150 | W |
| Derating factor | | 1.0 | W/ $^\circ C$ |
| Single pulse avalanche energy (Note 5) | E_{AS} | 722 | mJ |
| Operating Junction and Storage Temperature Range | T_J, T_{STG} | -55 To 175 | $^\circ C$ |

Thermal Characteristic

| | | | |
|--|-----------------|-----|------|
| Thermal Resistance, Junction-to-Case ^(Note 2) | $R_{\theta JC}$ | 1.0 | °C/W |
|--|-----------------|-----|------|

Electrical Characteristics ($T_c=25^\circ C$ unless otherwise noted)

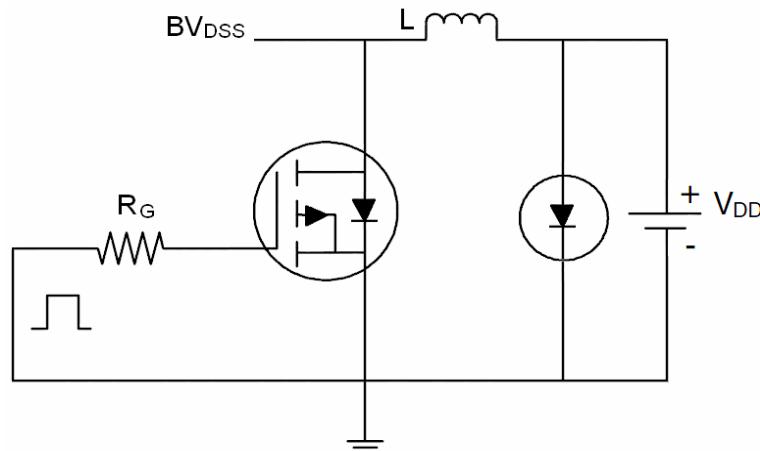
| Parameter | Symbol | Condition | Min | Typ | Max | Unit |
|--|--------------|---|------|------|-----------|-----------|
| Off Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | V_{DSS} | $V_{GS}=0V, I_D=-250\mu A$ | -60 | - | - | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS}=-60V, V_{GS}=0V$ | - | - | -1 | μA |
| Gate-Body Leakage Current | I_{GSS} | $V_{GS}=\pm 20V, V_{DS}=0V$ | - | - | ± 100 | nA |
| On Characteristics ^(Note 3) | | | | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}, I_D=-250\mu A$ | -1.2 | -1.8 | -2.4 | V |
| Drain-Source On-State Resistance | $R_{DS(ON)}$ | $V_{GS}=-10V, I_D=-20A$ | - | 11 | 13 | $m\Omega$ |
| | | $V_{GS}=-4.5V, I_D=-20A$ | - | 13 | 16 | $m\Omega$ |
| Forward Transconductance | g_{FS} | $V_{DS}=-5V, I_D=-20A$ | - | 25 | - | S |
| Dynamic Characteristics ^(Note 4) | | | | | | |
| Input Capacitance | C_{iss} | $V_{DS}=-30V, V_{GS}=0V, F=1.0MHz$ | - | 5604 | - | PF |
| Output Capacitance | C_{oss} | | - | 356 | - | PF |
| Reverse Transfer Capacitance | C_{rss} | | - | 265 | - | PF |
| Switching Characteristics ^(Note 4) | | | | | | |
| Turn-on Delay Time | $t_{d(on)}$ | $V_{DD}=-30V, R_L=1.5\Omega, V_{GS}=-10V, R_G=3\Omega$ | - | 18 | - | nS |
| Turn-on Rise Time | t_r | | - | 20 | - | nS |
| Turn-Off Delay Time | $t_{d(off)}$ | | - | 55 | - | nS |
| Turn-Off Fall Time | t_f | | - | 35 | - | nS |
| Total Gate Charge | Q_g | $V_{DS}=-30V, I_D=-20A, V_{GS}=-10V$ | - | 62.1 | - | nC |
| Gate-Source Charge | Q_{gs} | | - | 9.3 | - | nC |
| Gate-Drain Charge | Q_{gd} | | - | 16.8 | - | nC |
| Drain-Source Diode Characteristics | | | | | | |
| Diode Forward Voltage ^(Note 3) | V_{SD} | $V_{GS}=0V, I_S=-20A$ | - | | -1.2 | V |
| Diode Forward Current ^(Note 2) | I_S | | - | - | -82 | A |
| Reverse Recovery Time | t_{rr} | $T_J = 25^\circ C, I_F = -20A$ $di/dt = -100A/\mu s$ ^(Note 3) | - | 49 | - | nS |
| Reverse Recovery Charge | Q_{rr} | | - | 71 | - | nC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD) | | | | |

Notes:

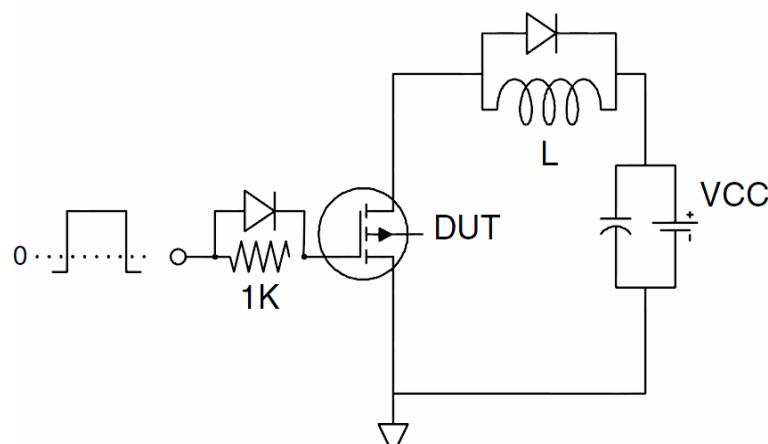
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. E_{AS} condition: $T_J=25^\circ C, V_{DD}=-30V, V_G=-10V, L=0.5mH, R_G=25\Omega$

Test Circuit

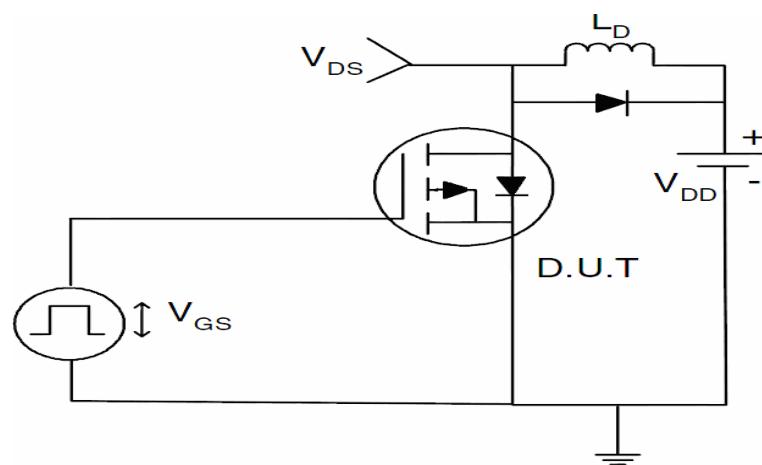
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

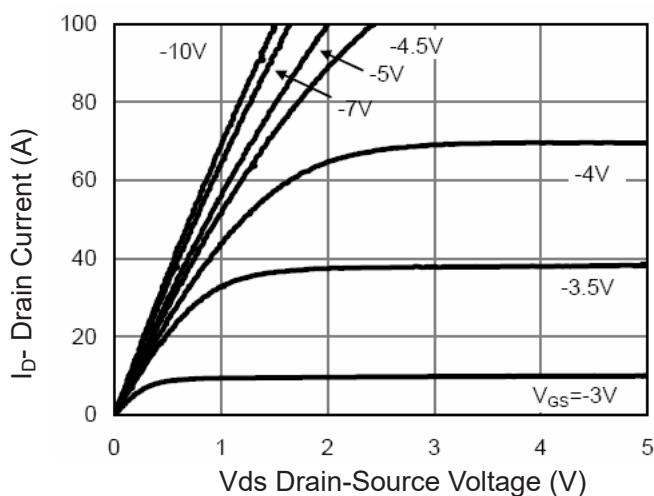


Figure 1 Output Characteristics

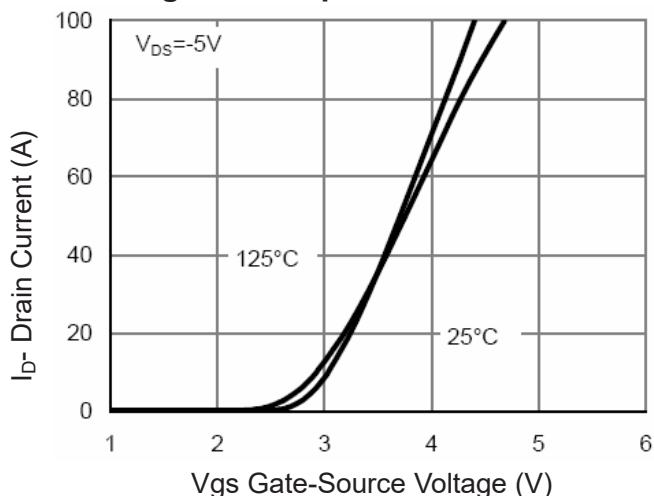


Figure 2 Transfer Characteristics

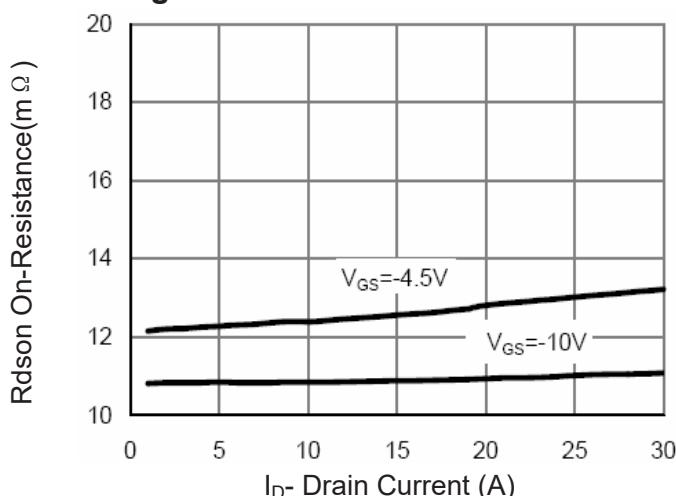


Figure 3 Rdson- Drain Current

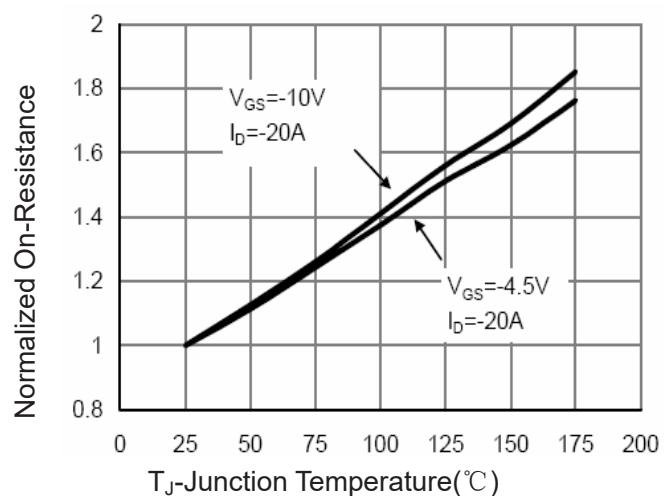


Figure 4 Rdson-Junction Temperature

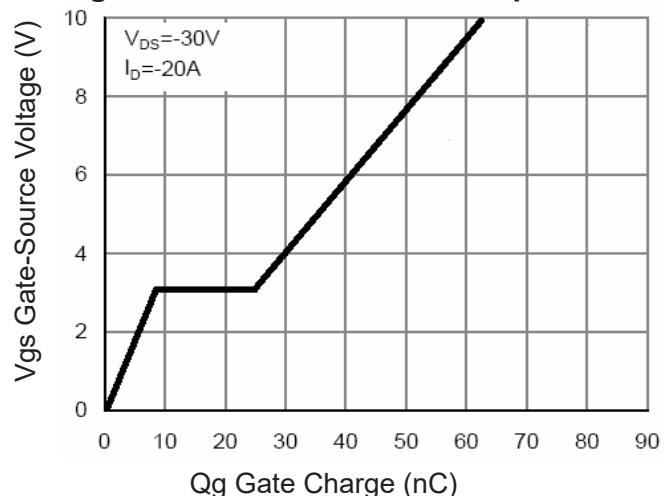


Figure 5 Gate Charge

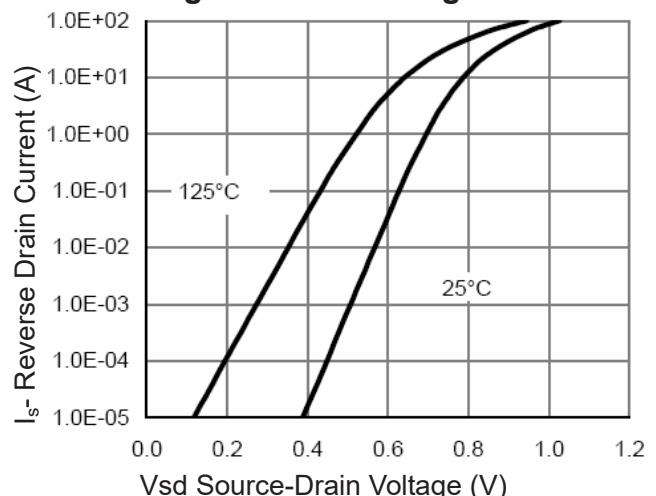
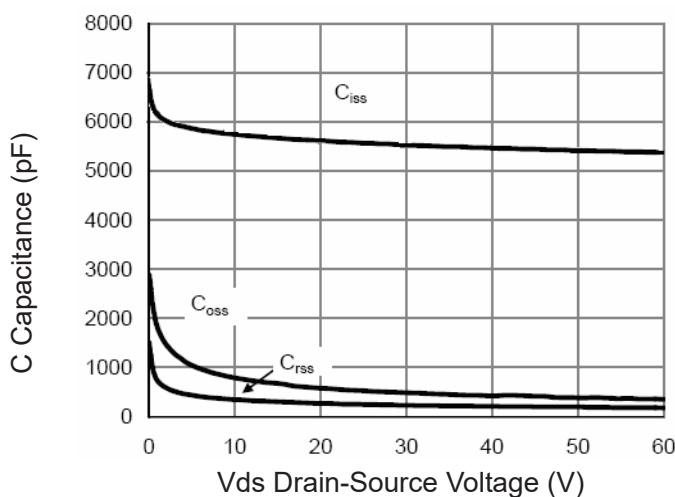
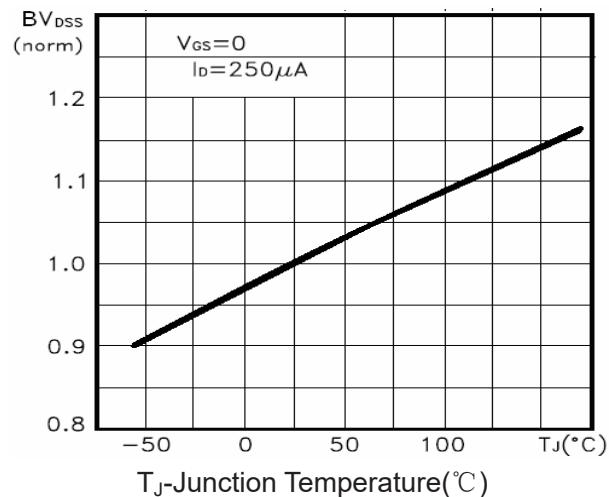
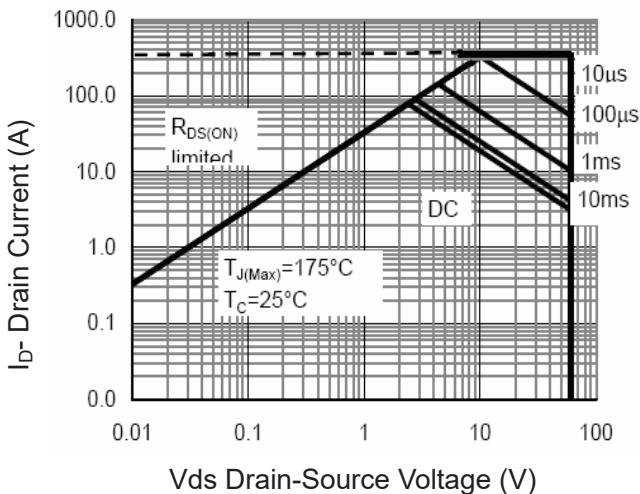
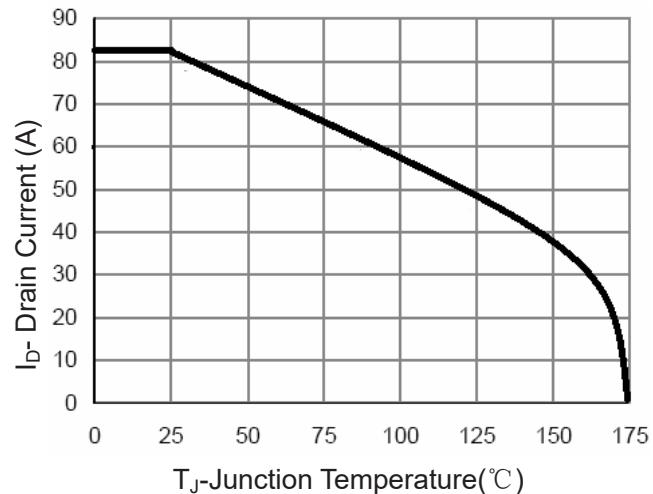
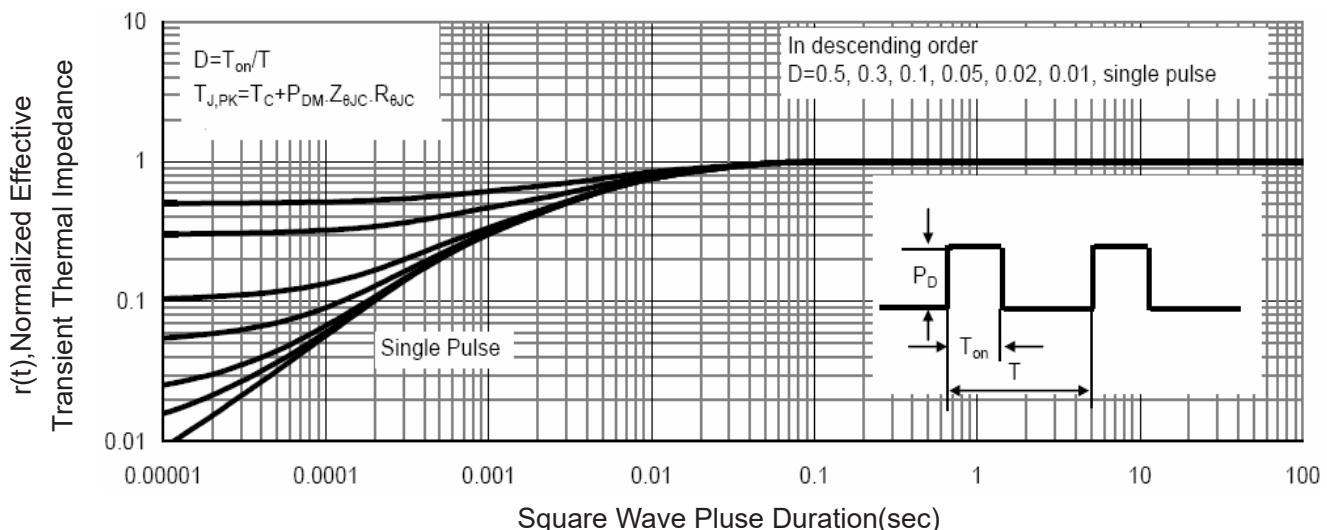


Figure 6 Source- Drain Diode Forward


Figure 7 Capacitance vs Vds

Figure 9 BV_{DSS} vs Junction Temperature

Figure 8 Safe Operation Area

Figure 10 I_D Current Derating vs Junction Temperature

Figure 11 Normalized Maximum Transient Thermal Impedance